

Notice of References Cited	Application/Control No. 10/725,133	Applicant(s)/Patent Under Reexamination LEE ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0113936	08-2002	Yanagawa et al.	349/155
*	B	US-2002/0044249	04-2002	Hirota, Naoto	349/146
*	C	US-2001/0040647	11-2001	Song et al.	349/43
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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